

信頼性試験結果 Reliability Test

XD6702D シリーズ

XD6702D Series

パッケージ Package	SOT-89-5
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AEC-Q100 Grade 2

RoHS対応品 / RoHS Compliance

ハロゲン&アンチモンフリー / Halogen & Antimony-Free

No.	Test Item	Test Conditions	Hours	Sample Size/Lot	Number of Lots	Result r/n
1	PC Preconditioning	TC(-40°C to 60°C 5cyc)→85°C/85%RH168h→260°CReflow Moisture Sensitivity Level 1 Moisture Preconditioning for THB, UHST & TC	3 times	77	3	0/231
2	HAST Highly Accelerated Stress Test	130°C85%RH VIN=38.0V Static Bias	100	77	3	0/231
3	TC Temperature Cycle	-65°C to 150°C	1000CYC.	77	3	0/231
4	PTC Power Temperature Cycle	-40°C to 105°C The power applied to the device is alternately turned on and off for 5 minutes.	1000	45	1	0/45
5	HTSL High Temperature Storage Life	150°C	1000	45	1	0/45
6	HTOL High Temperature Operating Life	125°C VIN=38.0V Static Bias	1000	77	3	0/231
7	ELFR Early Life Failure Rate	125°C VIN=38.0V Static Bias	48	800	3	0/2400
8	SD Solderability	245°C	5 sec.	15	1	0/15 >95% lead coverage
9	HBM Electrostatic Discharge Human Body Model	R=1500Ω C=100pF ±2000V	3 times	5	1	0/5
10	CDM Electrostatic Discharge Charged Device Model	±1000V	3 times	5	1	0/5
11	LU Latch-Up	R=0Ω C=200pF ±100V	3 times	3	1	0/3
		I-Latch 100mA	3 times	3	1	0/3